

Source of uncertainty	Magnitude
$\tau_h$ energy scale	1.2%
Electron energy scale	1–2.5%
$\vec{p}_T^{\text{miss}}$ energy scale	Dependent upon $p_T$ and $\eta$
$\tau_h$ ID & isolation	5%
Electron ID & isolation & trigger	2%
$\mu$ ID & isolation & trigger	2%
Diboson normalization	5%
Integrated luminosity	2.5%
b-tagging veto	4.5% heavy flavor, 0.15% light flavor
Limited number of events	Statistical uncertainty in individual bins
Signal theoretical uncertainty	Up to 20%
Reducible background uncertainties	WH: shape and yield based WH: 10% yield ZH: 26–100% yield